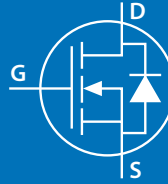


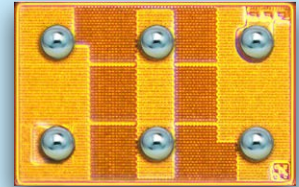
EPC2051 – Enhancement Mode Power Transistor

 $V_{DS}, 100\text{ V}$
 $R_{DS(on)}, 25\text{ m}\Omega$
 $I_D, 1.7\text{ A}$


Revised October 12, 2021

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Questions:
Ask a GaN
Expert



Die Size: 1.3 x 0.85 mm

EPC2051 eGaN® FETs are supplied in passivated die form with copper pillars.

Applications

- Open rack server architectures
- Lidar/pulsed power applications
- Power supplies
- Class D audio
- LED lighting
- Low inductance motor drive
- ToF module using Vcsel laser for camera modules, laptops and smart phones

Benefits

- Ultra high efficiency
- No reverse recovery
- Ultra low Q_G
- Ultra small footprint

Scan QR code or click link below for more information including reliability reports, device models, demo boards!


<https://l.lead.me/EPC2051>

Maximum Ratings

PARAMETER		VALUE	UNIT
V_{DS}	Drain-to-Source Voltage (Continuous)	100	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	120	
I_D	Continuous ($T_A = 25^\circ\text{C}$)	1.7	A
	Pulsed (25°C, $T_{PULSE} = 300\text{ }\mu\text{s}$)	37	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-40 to 150	$^\circ\text{C}$
T_{STG}	Storage Temperature	-40 to 150	

Thermal Characteristics

PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	3.8	$^\circ\text{C}/\text{W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	16	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	92	

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV _{DSS}	Drain-to-Source Voltage	V _{GS} = 0 V, I _D = 300 μA	100			V
I _{DSS}	Drain-Source Leakage	V _{DS} = 80 V, V _{GS} = 0 V		4	250	μA
I _{GSS}	Gate-to-Source Forward Leakage	V _{GS} = 5 V, T _J = 25°C		0.001	0.2	mA
	Gate-to-Source Forward Leakage [#]	V _{GS} = 5 V, T _J = 125°C		0.04	2	mA
	Gate-to-Source Reverse Leakage	V _{GS} = -4 V		4	250	μA
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 1.5 mA	0.8	1.4	2.5	V
R _{DS(on)}	Drain-Source On Resistance	V _{GS} = 5 V, I _D = 3 A		20	25	mΩ
V _{SD}	Source-Drain Forward Voltage [#]	I _S = 0.5 A, V _{GS} = 0 V		1.9		V

[#] Defined by design. Not subject to production test.

Dynamic Characteristics[#] ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C_{ISS}	Input Capacitance	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		224	297	pF
C_{RSS}	Reverse Transfer Capacitance			1		
C_{OSS}	Output Capacitance			86	129	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }50\text{ V}, V_{GS} = 0\text{ V}$		112		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			146		
R_G	Gate Resistance			0.8		Ω
Q_G	Total Gate Charge	$V_{DS} = 50\text{ V}, V_{GS} = 5\text{ V}, I_D = 3\text{ A}$		1.8	2.3	nC
Q_{GS}	Gate to Source Charge	$V_{DS} = 50\text{ V}, I_D = 3\text{ A}$		0.6		
Q_{GD}	Gate to Drain Charge			0.3		
$Q_{G(TH)}$	Gate Charge at Threshold			0.4		
Q_{OSS}	Output Charge	$V_{GS} = 0\text{ V}, V_{DS} = 50\text{ V}$		7.3	11	
Q_{RR}	Source-Drain Recovery Charge			0		

[#] Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

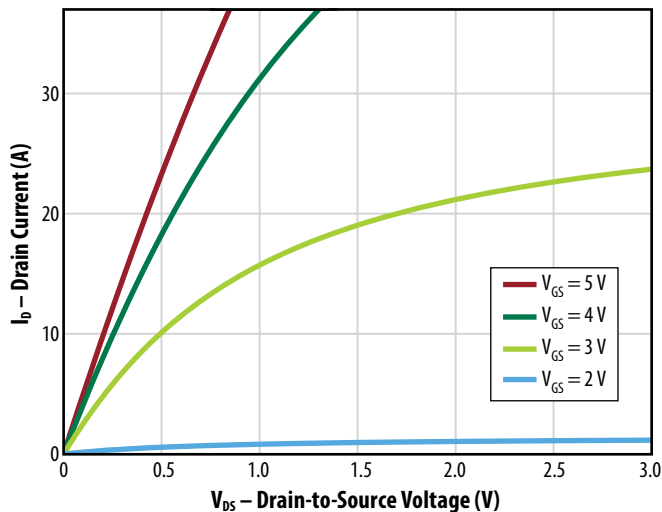
Figure 1: Typical Output Characteristics at 25°C 

Figure 2: Typical Transfer Characteristics

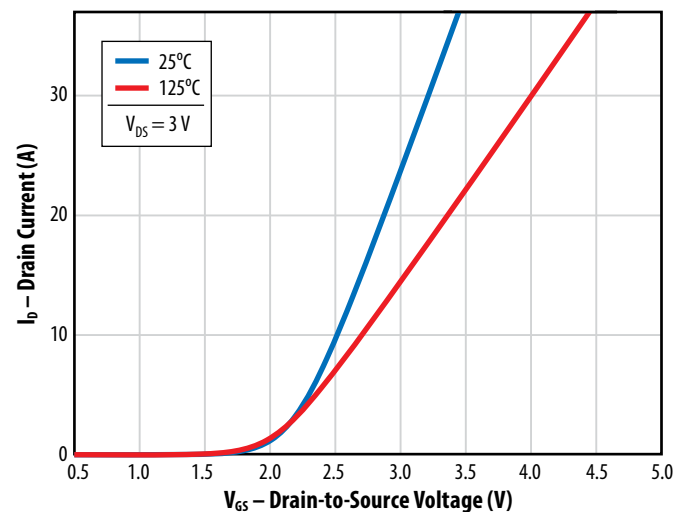
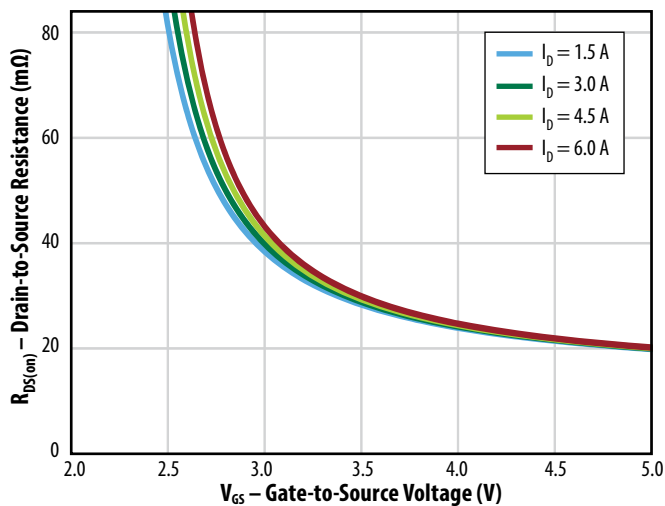
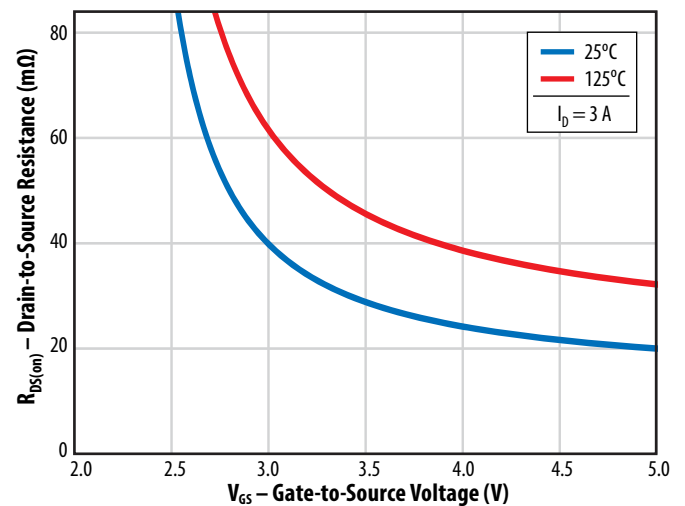
Figure 3: Typical $R_{DS(on)}$ vs. V_{GS} for Various CurrentsFigure 4: Typical $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

Figure 5a: Typical Capacitance (Linear Scale)

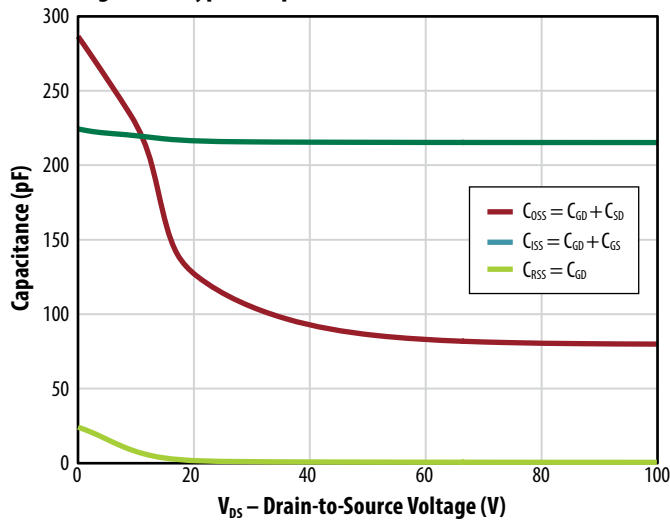


Figure 5b: Typical Capacitance (Log Scale)

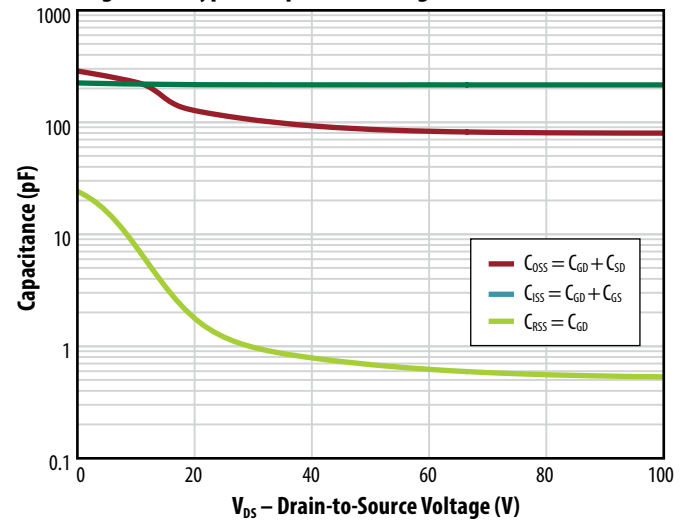
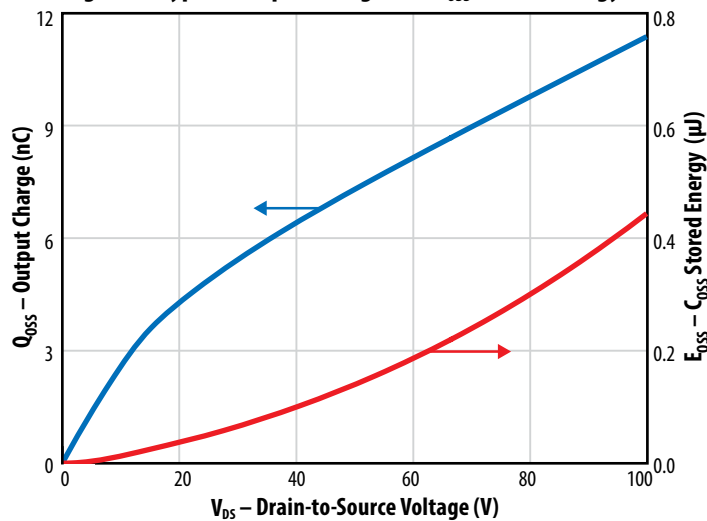
Figure 6: Typical Output Charge and C_{OSS} Stored Energy

Figure 7: Typical Gate Charge

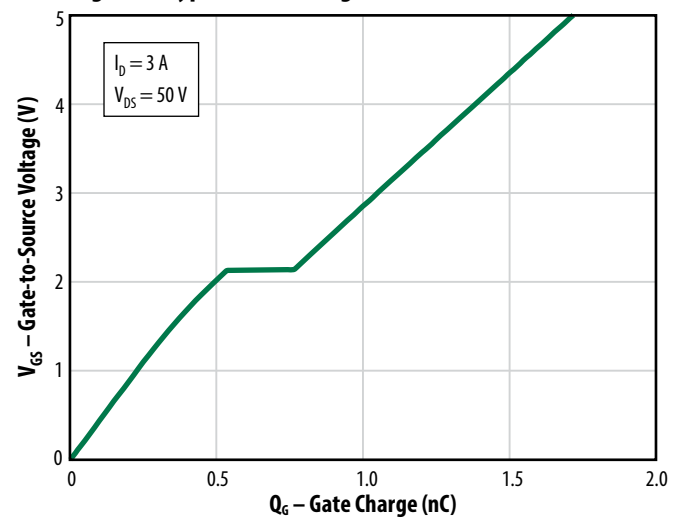


Figure 8: Typical Reverse Drain-Source Characteristics

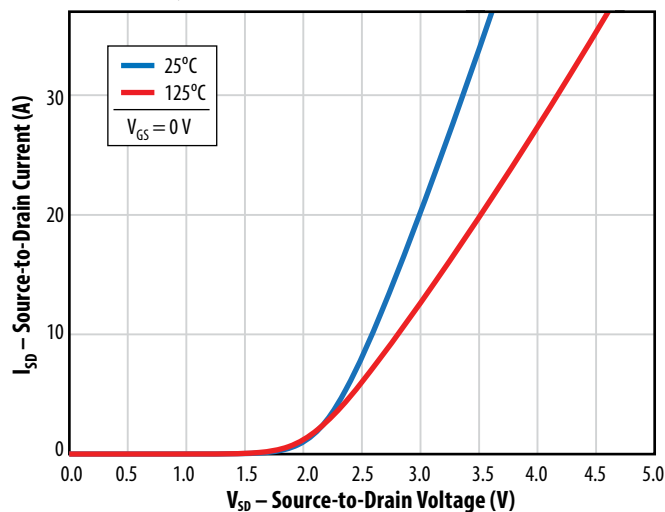
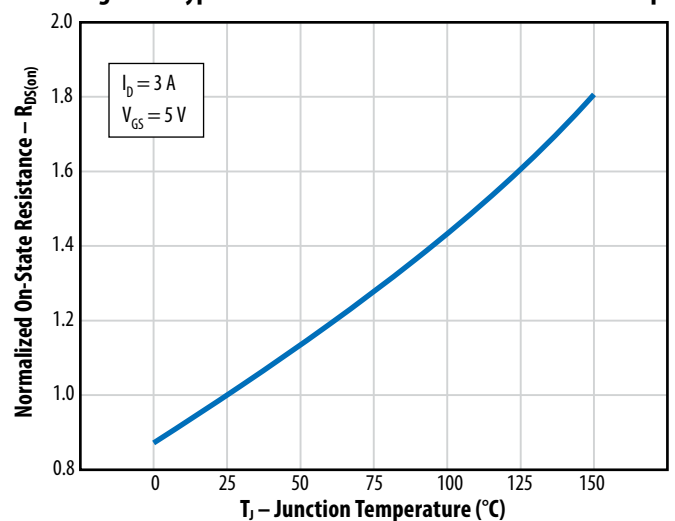


Figure 9: Typical Normalized On-State Resistance vs. Temp.



Note: Negative gate drive voltage increases the reverse drain-source voltage.
EPC recommends 0 V for OFF.

Figure 10: Typical Normalized Threshold Voltage vs. Temp.

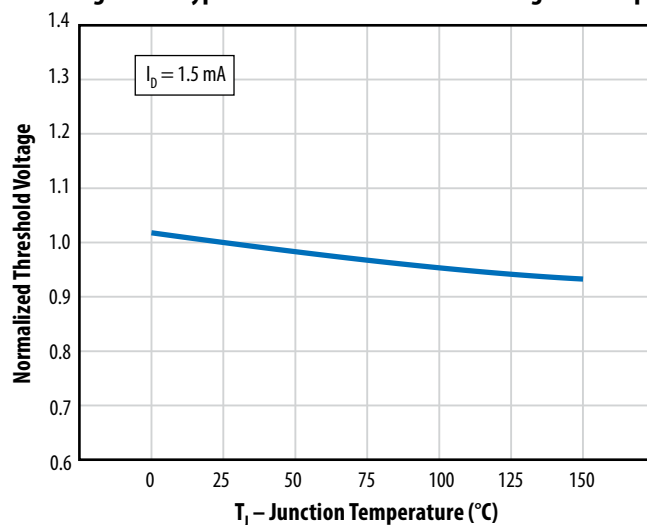


Figure 11: Typical Transient Thermal Response Curves

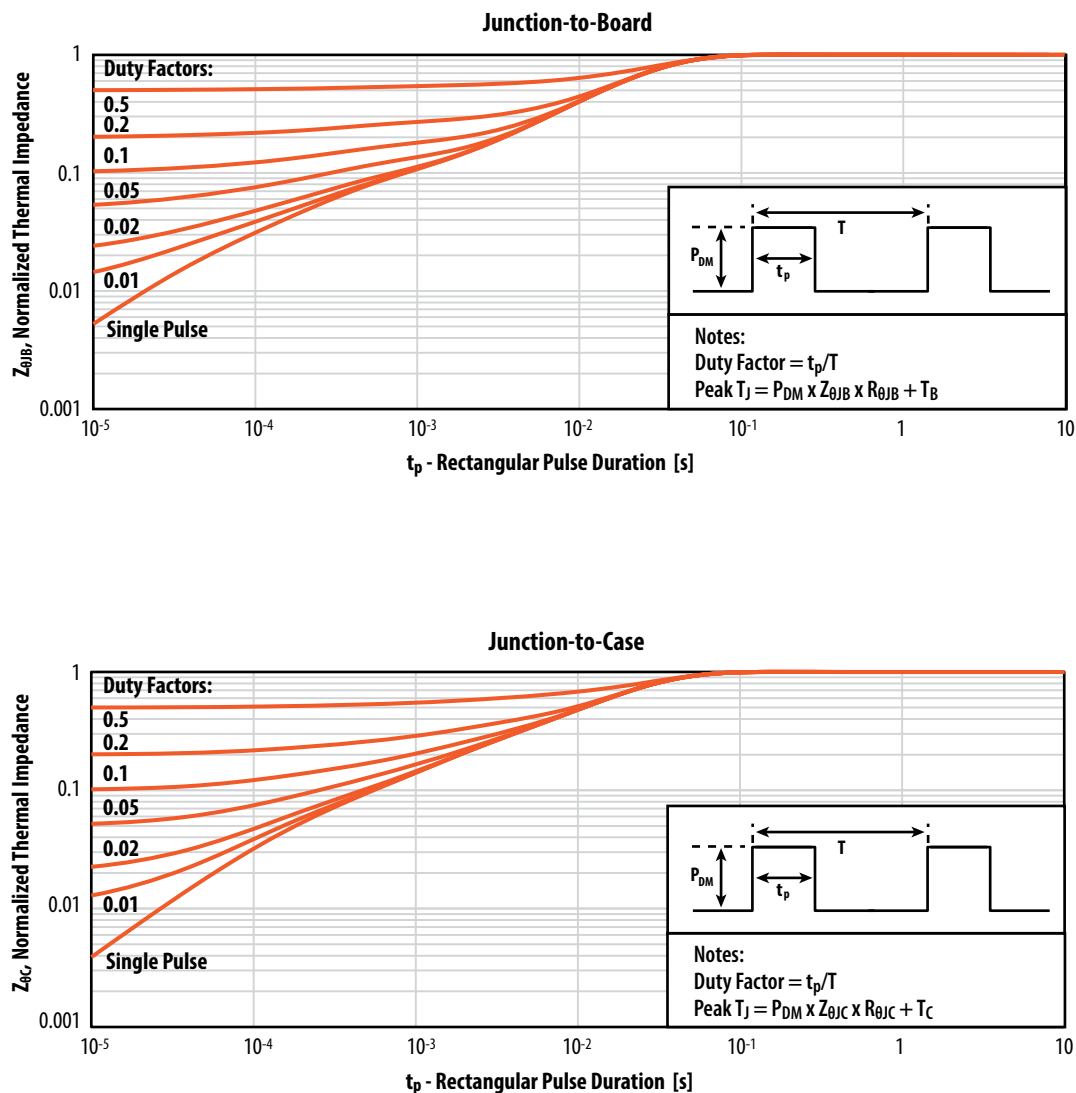
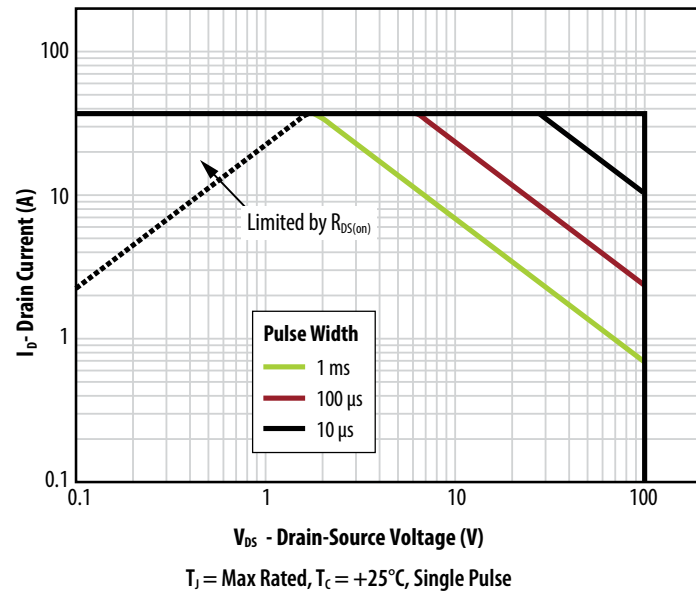
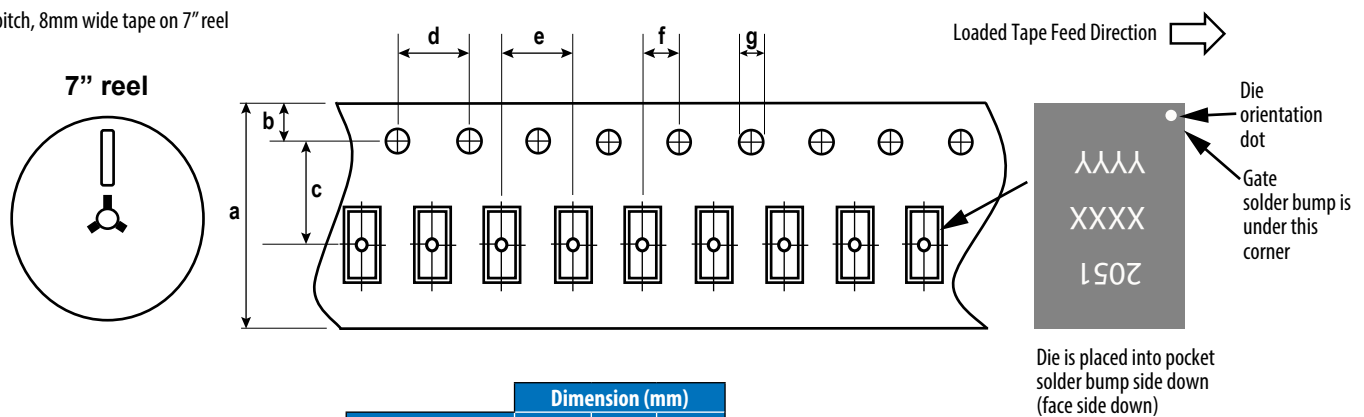


Figure 12: Safe Operating Area



TAPE AND REEL CONFIGURATION

4mm pitch, 8mm wide tape on 7" reel

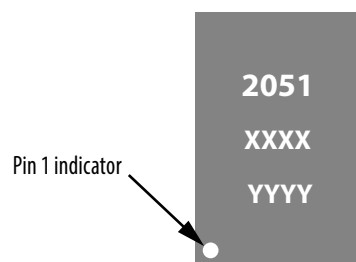


EPC2051 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (Note 2)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

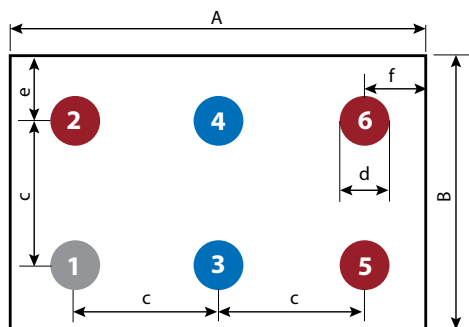
DIE MARKINGS



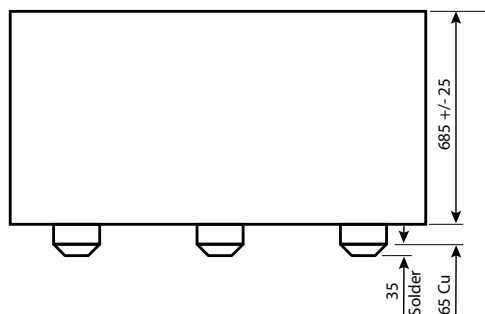
Part Number	Laser Markings		
	Part # Marking Line 1	Lot _ Date Code Marking Line 2	Lot _ Date Code Marking Line 3
EPC2051	2051	XXXX	YYYY

DIE OUTLINE

Solder Bar View
(looking at the Cu pillars)



Side View



DIM	MICROMETERS		
	MIN	Nominal	MAX
A	1270	1300	1330
B	820	850	880
c		450	
d		150	
e	185	200	215
f	185	200	215

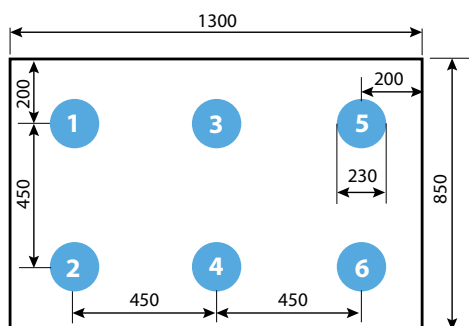
Pad 1 is Gate;

Pads 2, 5, 6 are Source;

Pads 3 & 4 are Drain

RECOMMENDED LAND PATTERN

(units in μm)



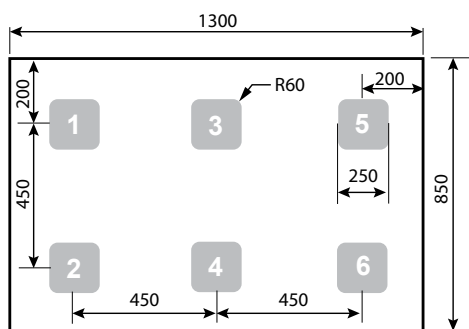
Pad 1 is Gate;

Pads 2, 5, 6 are Source;

Pads 3 & 4 are Drain

RECOMMENDED STENCIL DRAWING

(measurements in μm)

**Preliminary Solder Flux Recommendation:**

EPC uses Kester NP505-HR Type 4 Solder Paste. This solder uses ROL0 type flux. It is intended that the solder completely wets the sides of the Cu Pillar. This is different from traditional Cu Pillar assembly techniques.

Additional assembly resources available at

<https://epc-co.com/epc/design-support>

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